

**Notice of References Cited**

Application/Control No.

10/814,374

Applicant(s)/Patent Under  
Reexamination  
PERI ET AL.

Examiner

Insun Kang

Art Unit

2193

Page 1 of 2

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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Page 2 of 2

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	K	US-			
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	M	US-			

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